# **Probabilistic view**

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# Why probability?

- Machine learning often deals with random quantities
- Sources of uncertainty:
  - Inherent stochasticity of the system being modelled
  - Lack of information
  - Incomplete modelling (discarding information for the sake of simplicity, computability, etc.)

# Probability recap

# Probability

#### Frequentist:

relative frequency of occurrence of an experiment's outcome, when repeating the experiment

#### Example: coin toss

Toss a coin N times (H – number of 'heads', T – number of 'tails') Probability:

$$P('\text{head}s') = \lim_{N \to +\infty} \frac{H}{N}$$

$$P('\text{tails'}) = \lim_{N \to +\infty} \frac{T}{N} = 1 - P('\text{head}s')$$

# **Probability**

- Frequentist:
  - relative frequency of occurrence of an experiment's outcome, when repeating the experiment
- Bayesian:
  - degree of belief

**Example:** doctor analyzes a patient and says that the patient has 40% probability of having the flu (we can't "repeat" this patient)

#### Random variable

- A variable that can take values randomly
- Can think of it as variable enumerating possible outcomes of a random event
  - E.g., for the coin toss:

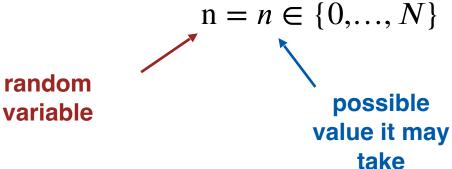
$$x = \begin{cases} 0, \text{ 'heads'} \\ 1, \text{ 'tails'} \end{cases}$$

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A bit more complex example – number of coin tosses with 'heads' out of N tosses total:



# Probability mass function (PMF)

- Defined for discrete variables
- Equals to probability for the variable x to take a given value x:

$$P(\mathbf{x} = \mathbf{x})$$

- or just P(x) omitting the name of the variable
- Joint probability distribution probability for several random variables to take some particular values simultaneously:

$$P(x = x, y = y) \equiv P(x, y)$$

- PMF must:
  - be defined on all possible states of the variable
  - take values in the [0, 1] interval
  - sum to 1 over all possible outcomes (probability for anything to happen)

# Probability density function (PDF)

- Defined for continuous variables
- Equals to:

$$p(x) = \lim_{\delta x \to 0} P(x \in (x, x + \delta x)) / \delta x$$

- PDF must:
  - be defined on all possible states of the variable
  - be  $\geq 0$  (can be higher than 1 though)
  - integrate to 1 over all possible outcomes (probability for anything to happen):

$$\int_{X} p(x)dx = 1$$

# Expectation and variance

Expectation:

For a discrete variable

$$\mathbb{E}[\mathbf{x}] = \sum_{\mathbf{X}} x P(\mathbf{x})$$

For a continuous variable

$$\mathbb{E}[\mathbf{x}] = \int_{X} x p(\mathbf{x}) d\mathbf{x}$$

- Meaning: average outcome
- Variance:

$$Var[x] = \mathbb{E}\left[ (x - \mathbb{E}[x])^2 \right] = \mathbb{E}\left[ x^2 \right] - (\mathbb{E}[x])^2$$

Meaning: spread of the outcomes

#### Some distributions

Uniform[a, b]:

$$p(x) = \frac{1}{b-a} = const$$

Binomial:

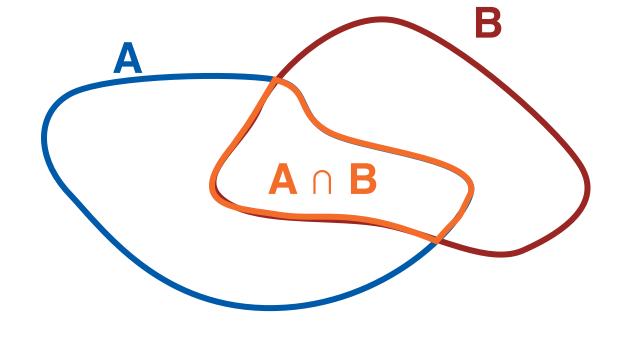
$$P(k) = \frac{n!}{k!(n-k)!} p^{k} (1-p)^{n-k}$$

Normal distribution:

$$p(x) \equiv \mathcal{N}(x \mid \mu, \sigma^2) = \frac{1}{\sqrt{2\pi\sigma^2}} e^{-\frac{(x-\mu)^2}{2\sigma^2}}$$

# Conditional probability

$$P(A \mid B) = \frac{P(A \cap B)}{P(B)}$$



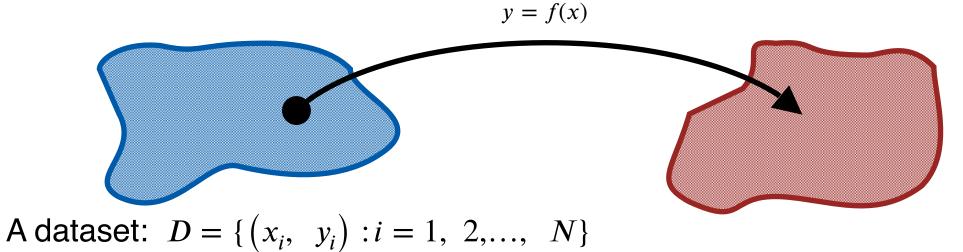
For PDF: 
$$p(x|y) = \frac{p(x,y)}{p(y)}$$

- i.e. we're renormalizing p(x, y) as a distribution of only x for some fixed y

# Probabilistic view on supervised learning

 $\mathcal{X}$  – a set of objects

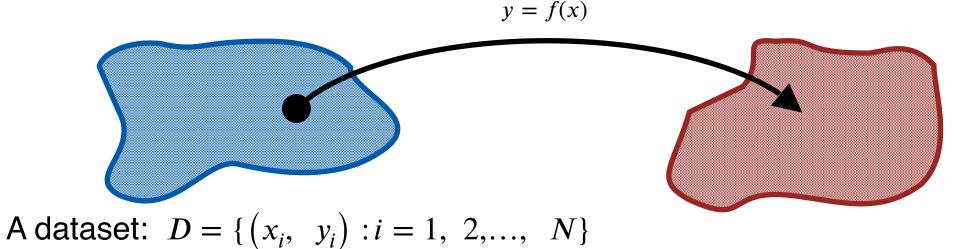
 $\mathcal{Y}$  – a set of targets



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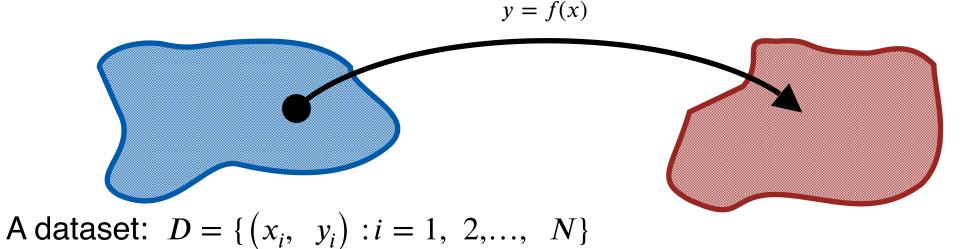


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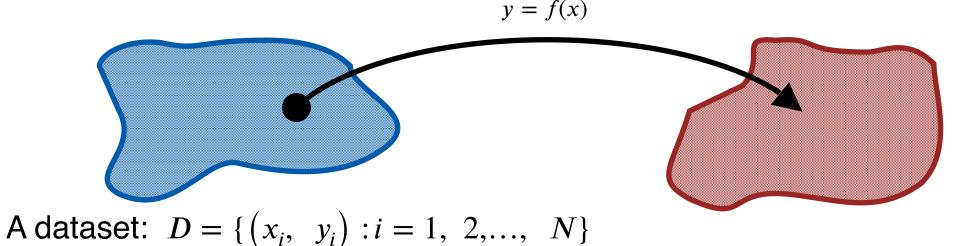


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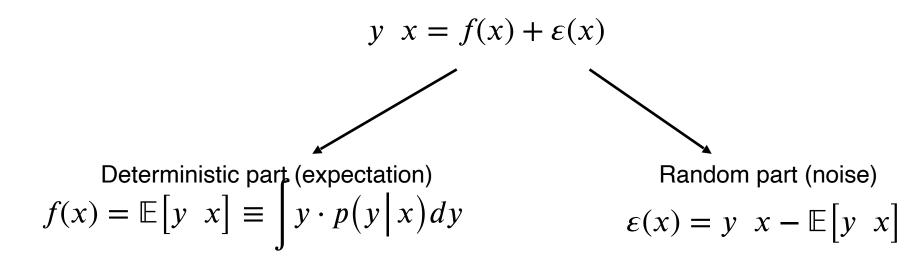


$$x_i \in \mathcal{X}, \ y_i = f(x_i) \in \mathcal{Y}$$

- There's some underlying probability distribution p(x, y)
- $-(x_i, y_i)$  are drawn from p(x, y), independently for each i
- Can also say that for a given  $x_i$ , the target  $y_i$  is drawn from p(y | x)

### Deterministic and stochastic components

With this view, we can separate deterministic and stochastic parts of the true mapping:



Let's make an assumption about data:

$$y x = f(x) + \varepsilon$$

Assume that label noise is normally distributed:

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We want our model  $\hat{f}_{\theta}(x)$  to fit the true dependence f(x), i.e. we define a probabilistic model:

$$y \ x \sim \mathcal{N}\left(\hat{f}_{\theta}(x), \ \sigma_{\varepsilon}^{2}\right)$$

Our model can be fitted with the **maximum likelihood** approach:  $I = \prod_{x \in \mathcal{X}} \mathcal{N}(x) \stackrel{\wedge}{f}(x) = \mathbb{Z}^2$ 

 $L = \prod_{i=1}^{N} \mathcal{N}\left(y_i \middle| \hat{f}_{\theta}(x_i), \ \sigma_{\varepsilon}^2\right) \to \max_{\theta}$ 

"The observed data is most probable"

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$$= \mathbb{C} \cdot \sum_{i=1...N} \left( y_i - \hat{f}_{\theta}(x_i) \right)^2 + const \to \min_{\theta}$$

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MSE loss \iff Prob.
$$= \mathbb{C} \cdot \sum_{i=1...N} \left( y_i - \hat{f}_{\theta}(x_i) \right)^2 + const \to \min_{\theta}$$

label noise!

# Summary

- Machine Learning often deals with randomness (intrinsic, lack of information, incomplete modelling)
- Supervised learning problems can be posed in the probabilistic context
- The mapping between features and labels can be decomposed into deterministic and stochastic parts
- There's a probabilistic model behind the loss function

Food for thought: what probabilistic model would correspond to minimizing MAE loss:  $\frac{1}{N} \sum_{i} \left| y_i - \hat{f}(x_i) \right|$ ?